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MACHINE LEARNING CONCEPTS IN MATERIAL ANALYTICS: **CLASSIFICATION OF PLASTIC MATERIALS**

Samples

Imaging method

analytics

σ

Data

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INTRODUCTION AND MOTIVATION

High-throughput classification of plastic types

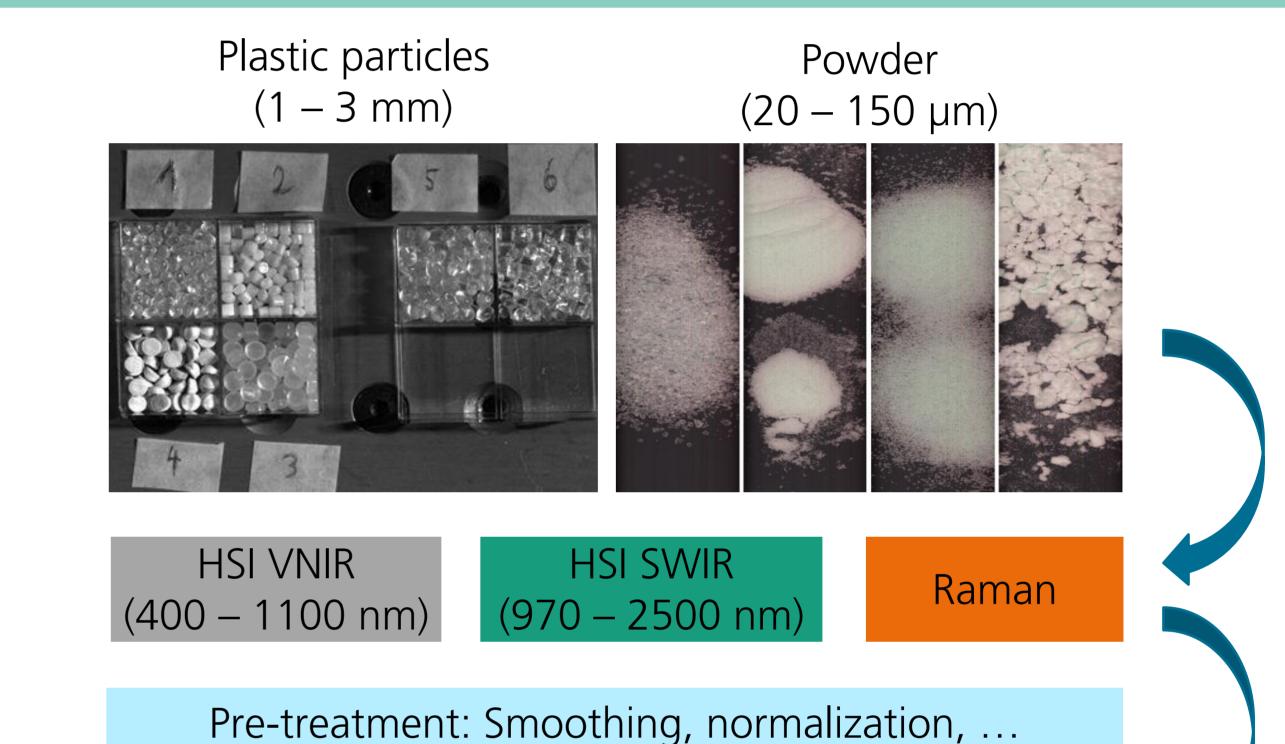
- **1. Example: Microplastic** detection and classification: Increasing contamination of water and air requires fast analytic routines
- **2.** Example: Recycling of compound materials (e.g. photovoltaic modules): Separation of materials requires separation of materials



Challenge: Automated and universal data analysis approaches for spectral imaging techniques (e.g. Raman spectroscopy, FTIR, hyperspectral imaging)

TEST SAMPLES AND IMAGING METHODS

DATA ACQUISITION AND ANALYTICS APPROACH



Typical sample setup:

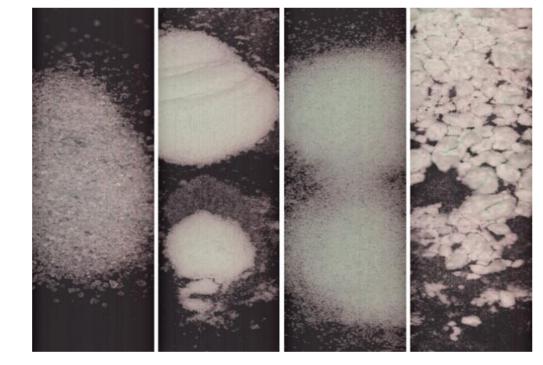
- . Six types of plastics analyzed (PP, PS, PVC, PET, PA, PE)
- 2. Large samples, powder and micro-particles
- Environment: air or water 3.

Hyperspectral imaging (HSI):

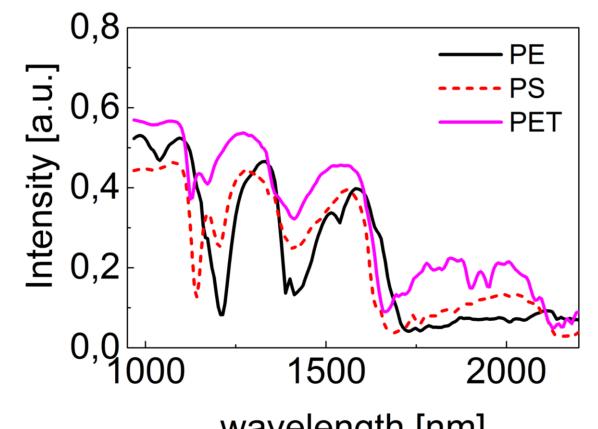
- Measurement of spatially resolved reflection spectra in visible and infra-red wavelengths
- 2. Large data set of high-dimensional data: each pixel with entire spectral information

Raman spectroscopy:

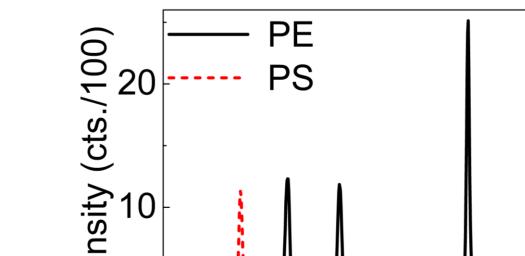
- 1. Measurement of material properties by inelastic scattering of light
- 2. Large data set of high-dimensional data:



Example: plastic powder



wavelength [nm]



Dimensionality reduction

Classification (supervised, unsupervised)

SVM with RBF kernel

Component 1

2dim LDA for Raman

★ Background

PA

PS

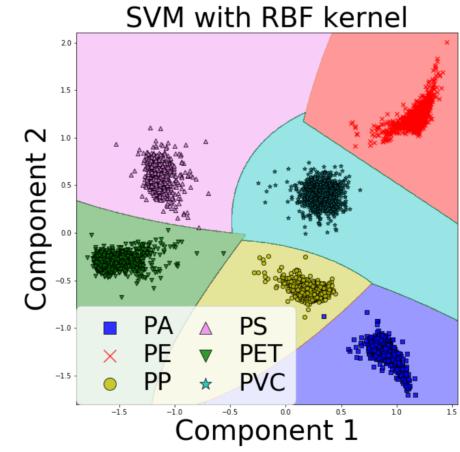
PE

RESULTS: VERY HIGH CLASSIFICATION RATES ACHIEVABLE

Classification models: Support vector machine

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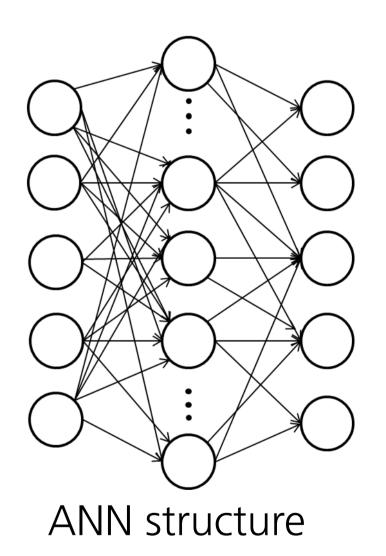
Component



2dim LDA for HSI

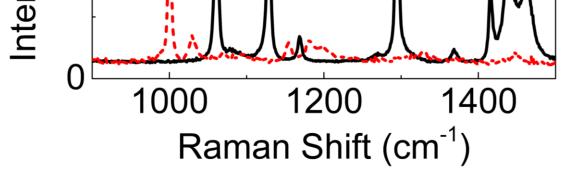
		predicted class							
		PA	PE	PP	PS	PET	PVC		
actual class	PA	1084	0	1	0	0	0		
	PE	0	1032	0	0	0	0		
	PP	0	0	1133	0	0	0		
	PS	0	0	0	1077	0	0		
	PET	0	0	0	0	1008	0		
	PVC	0	0	0	0	0	1091		

Artificial neural net



	predicted class									
	PA	PE	PP	PS	PET	PVC				
PA	1085	0	0	0	0	0				

each pixel with entire spectral information



Spectroscopic material analytics:

- Measurements yields large data sets (one spectrum for each pixel)
- Efficient, automated and universal data algorithms required
- Machine learning approach and artificial neural nets

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1032 PE 0 0 0 0 class 0 1133 PP 0 0 0 0 actual PS 1077 0 0 0 0 0 | PET 1008 0 0 0 0 0 **PVC** 0 2 1087 2 0 0

Confusion matrix HIS – SVM

Confusion matrix HSI – ANN



- Machine learning and artificial neural nets:
- > Almost perfect classification achievable on test system
- Raman and Hyperspectral imaging as data basis possible
- Both methods reliable (support vector machines or neural nets)